What is claimed is:

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- 1 1. An A/D converter, comprising:
- 2 a plurality of capacitors and at least one comparator,
- 3 arranged to form an analog to digital conversion of an analog
- 4 input signal to a digital output signal; and
- 5 a control circuit, controlling said capacitors to be used
- 6 for both analog to digital conversion and for calibration.
 - 2. A converter as in claim 1, wherein said control circuit controls a level which is supplied to said capacitors.
 - 3. A converter as in claim 1, further comprising a plurality of level latches, storing levels associated with calibration, and connected to control respective levels applied to said capacitors.
- 1 4. A converter as in claim 2, wherein said control circuit
- 2 controls a level which is supplied to a bottom plate of each
- 3 said capacitor, and wherein a top plate of each said capacitor
- 4 is connected together to form a common line.
- 1 5. A converter as in claim 2, further comprising an image
- 2 acquisition element, obtaining information indicative of a

- 3 portion of an image, and producing an output indicative thereof,
- 4 said an output being analog to digitally converted by said
- 5 analog to digital converter.
- 1 6. A converter as in claim 4, wherein said level supplied
- 2 to a bottom plate of each said capacitors can be one of two
- 3 different voltage levels or a ground level.
- 7. A converter as in claim 4, wherein said level applied
 2 to a bottom plate of each capacitor can be a first voltage level
 - which is double a value of said first voltage level.
 - 8. A converter as in claim 5, wherein said image acquisition element is a MOS element.
- 9. A converter as in claim 8, wherein said image
- 2 acquisition element is one of a MOS photo diode or a MOS photo
- 3 gate, and forms an active pixel sensor.
- 1 10. A converter as in claim 1, wherein said control
- 2 circuit includes a latch, latching a level which is supplied to
- 3 a bottom plate of each of a plurality of capacitors.

- 1 11. A converter as in claim 10, wherein said level can be
- 2 one of ground or one of two voltage levels.
- 1 12. A converter as in claim 10, wherein said level can be
- 2 one of ground or a single voltage level.
- 1 13. A converter as in claim 12, further comprising a
- 2 plurality of level latches, respectively storing levels
- 3 associated with calibration, and connected to control a level
- 4 applied to said capacitors.
- 1 14. A converter as in claim 13, wherein said level latches
- 2 store a negative version of a calibration level.
- 1 15. A converter as in claim 14, wherein said negative
- 2 version is a two's compliment.
- 1 16. An A/D converter comprising:
- 2 a plurality of capacitors, each associated with a specified
- 3 bit of the digital signal, and each having a top plate connected
- 4 to a common line and a bottom plate, and a comparator, connected
- 5 to receive said common line as an output of said capacitor at
- 6 one input, and a signal at another input; and

- 7 a plurality of value latches, each storing a value, and
- 8 each associated with one of said plurality of capacitors, and
- 9 changing a value applied to said bottom plate of said capacitor.
- 1 17. A converter as in claim 16, wherein said latches store
- 2 either a one or a zero, and apply either a ground level or a
- 3 reference level to said capacitor bottom plates depending on the
- 4 value stored by said latches.

- 18. A converter as in claim 16, further comprising a control circuit, controlling said value latches to store a calibration value, and use said calibration value during converting.
 - 19. A converter as in claim 18, wherein the same said capacitors are used both for calibration and for A/D conversion.
 - 1 20. A converter as in claim 17, wherein said reference
 - 2 level includes two reference levels, one higher than the other.
 - 1 21. A converter as in claim 17, wherein said reference
 - 2 level includes a single reference level.

- 1 22. A converter as in claim 17, further comprising a
- 2 switch, controlled by a level in said latch, and selectively
- 3 providing either a ground level or a reference level to said
- 4 capacitor.
- 1 23. A converter as in claim 18, further comprising an
- 2 image sensing element, producing an output signal indicative of
- 3 a portion of said image, said output signal being coupled to
- 4 said plurality of capacitors and comparator to be A/D converted
- 5 thereby.
 - 24. A converter as in claim 23, wherein said image sensing
- 2 element is an element formed in MOS.
 - 25. A converter as in claim 23, wherein said image sensing
- 2 element is an active pixel sensor, having a photoreceptor, a
- 3 follower associated with said photoreceptor, and a selector
- 4 which allows electronic selection, also associated with said
- 5 photoreceptor.
- 1 26. A converter as in claim 25, wherein said image sensing
- 2 element is one of a photo diode or a photo gate.

- 27. A converter as in claim 25, wherein said follower and 1
- said selector are each formed using CMOS. 2
- 1 28. A converter as in claim 27, wherein said value latches
- are each formed using CMOS. 2
- 1 29. A converter as in claim 28, wherein said value
- latches, said comparator and said capacitors, and a plurality of 2
- 3 said image sensing elements, are each formed on a common
- substrate.
- 30. A converter as in claim 18, wherein said value latches
- Hall day Hall 31. A converter as in claim 18, wherein said value latches
 - store a value calibration value.

are formed of CMOS.

- 1 A converter as in claim 18, wherein said value latches
- 2 store a negative of a calibration value.
- 1 33. A method, comprising:
- calibrating an A/D converter using first capacitors; 2
- obtaining a signal to be converted by said A/D converter; 3
- 4 and

- 5 converting said signal to digital using at least a
- 6 plurality of said first capacitors for said converting.
- 1 34. A method as in claim 33, further comprising obtaining
- values associated with said calibrating, and storing said values 2
- 3 in a memory.
- 1 A method as in claim 34, wherein said memory includes
- 2 a plurality of bits associated with said capacitors, each bit
- 3 4 4 7 7 storing a value which adjusts a level that is applied to each
 - said capacitor.
 - A method as in claim 35, wherein said level is applied to a bottom plate of said capacitor, and a conversion is carried
 - out using a top plate of said capacitor.
- 3 A method as in claim 33, further comprising applying a
 - 2 calibration level to at least one of said capacitors.
 - 1 38. A method as in claim 33, further comprising storing a
 - 2 calibration level obtained during said calibrating, and using
 - 3 the stored calibration level to apply a calibration level to at
 - least one of said capacitors based on a level of said 4
 - 5 calibration.

- 1 39. A method as in claim 38, wherein said level includes a
- 2 single reference level and a ground level.
- 1 40. A method as in claim 38, wherein said level includes
- 2 two different reference levels and a ground level.
- 1 41. A method as in claim 33, further comprising obtaining
- 2 a signal indicative of a portion of an image, and using said
- signal for said converting.

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 42. A method as in cl
 2 signal comprises attaining

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- 42. A method as in claim 41, wherein said obtaining a signal comprises attaining a signal on the same substrate as said A/D converter.
- 43. A method as in claim 34, wherein said values include values directly obtained from said calibrating.
- 1 44. A method as in claim 34, wherein said values include
- 2 complements of values obtained during said calibrating.
- 1 45. A method as in claim 33, wherein said calibrating
- 2 further comprising obtaining a complement of a calibration level
- 3 and storing said complement in a plurality of latch elements.

- 1 46. A method as in claim 33, further comprising storing a
- 2 level associated with said calibrating in a plurality of latch
- 3 elements, associating each of said latch elements with one of
- 4 said first capacitors, and using said values to adjust a level
- 5 on said capacitors according to a calibration level, during
- 6 obtaining a signal.
- 1 47. A method, comprising:
- $^{\circ}$ 2 obtaining a value indicative of calibration of an A/D
- 3 converter using a plurality of capacitors to obtain said value;
- 4 storing said value in a latch associated with the A/D
- 5 converter; and
- 6 converting an input value using said plurality of
- 7 capacitors, and using said value stored in said latch.
- 1 48. A method as in claim 47, wherein said value stored in
- 2 said latch is a multiple bit value, and associating its of said
- 3 value stored in the latch with individual ones of said plurality
- 4 of capacitors.
- 1 49. A method as in claim 48, further comprising using said
- 2 value stored in said us a value of said capacitor.

- 1 50. A method as in claim 48, further comprising using said
- value to adjust a level applied to a bottom plate of said 2
- capacitor. 3
- 51. A method as in claim 47, wherein said input value is a 1
- 2 value indicative of a portion of an image.
- An active pixel sensor, comprising: 1
- 2 a semiconductor substrate, having a plurality of items
- **1** 3 formed thereon, said items including:
- 4 an image acquisition element, formed using MOS formation
 - technology, and having an MOS follower associated therewith and
- Maria Hang an MOS selection transistor associated therewith, said image
 - acquisition element producing an output signal indicative
- **19** 8 thereof; and
 - an A/D converter element, also formed using MOS formation
 - 10 technology, including a plurality of capacitors and a
 - 11 comparator, said plurality of capacitors operating both to
 - 12 calibrate said A/D converter element and to convert signals
 - 13 applied to said A/D converter element, the same capacitors being
 - 14 used both for said calibrate and for said converter, and further
 - comprising a latch, having a plurality of digital storage 15
 - portions, each formed of CMOS, and each storing a value based on 16

- 17 said calibrate, said values used for allowing said A/D converter
- 18 to acquire signals.
- 1 53. A sensor as in claim 52, wherein said A/D converter is
- 2 a successive approximation A/D converter.

5